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David B. Chenault
Dennis H. Goldstein
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Introduction

This conference is the latest in a long series of conferences that address current research in optical polarization with an emphasis on remote sensing applications. It is the twelfth conference with the title (with some slight variation) *Polarization: Measurement, Analysis, and Remote Sensing*.

As improvements in imaging sensors, polarizer fabrication techniques, understanding of the Mueller matrix, and modeling fidelity occur, so too do we see improvements in the ability of polarization sensors to perform the tasks required in remote sensing. Subsequently, the results presented in this volume proceedings are evidence of this.

The *Polarization* conference series started in 1997 in San Diego, California, United States. Conferences prior to the current one in reverse chronological order are documented in Proceedings of SPIE Vols. 9099, 8364, 7672, 6972, 6240, 5432, 4819, 4481, 4133, 3754 and 3121.

The proceedings you have before you are made up of papers from seven conference sessions: one session addressed Mathematics and Modeling, two sessions focused on Instrumentation, two sessions described Applications and Measurements, and two others were devoted to Analysis.

We would like to express our sincere appreciation to our committee members, session chairs, and contributing authors whose combined efforts made this conference a success.

David B. Chenault
Dennis H Goldstein

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